


<b>Search Notes</b>  	<b>Application/Control No.</b>  10576787	<b>Applicant(s)/Patent Under Reexamination</b>  NEBASHI ET AL.
	<b>Examiner</b>  THIEM PHAN	<b>Art Unit</b>  3729

SEARCHED			
Class	Subclass	Date	Examiner
29	842, 740, 745, 832, 840, 860	7/1/08	TP
174	264	"	"
228	41, 180.21, 180.22, 245, 246	"	"
257	E21.508	7/1/08	TP

SEARCH NOTES			
Search Notes		Date	Examiner
EAST Search Attached		7/1/08	TP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner